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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/614,997	07/08/2003	Dennis Harold Burke JR.	TI34951	8166	
23494	7590 05/11/2006		EXAMINER		
	STRUMENTS INCORPO	CHUNG, PHUNG M			
P O BOX 655474, M/S 3999 DALLAS, TX 75265			ART UNIT	PAPER NUMBER	
•			2138		
			DATE MAILED: 05/11/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application	No.	Applicant(s)			
Office Action Summary		10/614,997		BURKE ET AL.			
		Examiner		Art Unit			
		Phung My C	•	2138			
Period fo	The MAILING DATE of this communication apor Reply	opears on the d	over sheet with the co	orrespondence ad	idress		
WHIC - Exte after - if NC - Failu Any	ORTENED STATUTORY PERIOD FOR REPLICATION OF THE MAILING ENGINEERS IS LONGER, FROM THE MAILING ENGINEERS IN COMMENTED THE MAILING ENGINEERS IN COMMENTED THE MAILING ENGINEERS IN COMMENT OF THE MAILING ENGINEERS	DATE OF THIS .136(a). In no event d will apply and will of te, cause the applica	S COMMUNICATION	l. ely filed the mailing date of this o) (35 U.S.C.§ 133).			
Status							
	Responsive to communication(s) filed on <u>28 F</u> This action is FINAL . 2b) This Since this application is in condition for allowed closed in accordance with the practice under	is action is not ance except fo	n-final. or formal matters, pro		e merits is		
Disposit	ion of Claims						
5)□ 6)⊠ 7)□	Claim(s) 1-34 is/are pending in the application 4a) Of the above claim(s) is/are withdra Claim(s) is/are allowed. Claim(s) 1-34 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or	awn from cons					
Applicati	ion Papers						
10)	The specification is objected to by the Examin The drawing(s) filed on is/are: a) acceptable and any objection to the Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examin	ccepted or b) e drawing(s) be ction is required	held in abeyance. See I if the drawing(s) is obje	37 CFR 1.85(a). ected to. See 37 C	• •		
Priority (under 35 U.S.C. § 119						
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 							
2) Notic 3) Inform	t(s) e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08 r No(s)/Mail Date	3) 5	i) Interview Summary (Paper No(s)/Mail Dai i) Notice of Informal Pa i) Other:	te	O-152)		

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Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all

obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains.

Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of

the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of

the various claims was commonly owned at the time any inventions covered therein

were made absent any evidence to the contrary. Applicant is advised of the obligation

under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was

not commonly owned at the time a later invention was made in order for the examiner to

consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g)

prior art under 35 U.S.C. 103(a).

2. Claims 1-34 are rejected under 35 U.S.C. 103(a) as being unpatentable over

Fintel et al (6,920,585) in view of Sugamori (6,536,006).

As per claims 1 and 3-4, Fintel et al disclose an apparatus comprising:

At least one processor (250); and

At least one device tester unit (220) coupled to the processor, wherein the

processor is configured to

Execute a first test ...;

Prepare execution of a second test...;

Process test data resulting from the first test; and

Executing the second test concurrently with the processing of the test data. (See col. 3, lines 5-31 and col. 5, lines 28-39). The apparatus of Fintel et al do not disclose for testing at least one mixed signal semiconductor device. However, Sugamori discloses an apparatus for testing at least one mixed signal semiconductor device (abtract and col. 7, lines 30-45). Therefore, it would have been obvious to a person of ordinary skill in the art, at the time the invention was made, to incorporate the apparatus for testing at least one mixed signal semiconductor device as taught by Sugamori into the test apparatus of Fintel to test at least one mixed signal semiconductor device so that different types of test, such as analog circuit test and digital circuit test can be performed at the same time.

As per claim 2, Sugamori further discloses wherein the mixed signal semiconductor testing a performed by a single processor (67).

As per claim 5, Fintel et al and Sugamori do not disclose that wherein the first and second tests are configured for one or more of wafer testing and package testing of the mixed signal semiconductor device. However, it would have been obvious to a person of ordinary skill in the electronic art, at the time the invention was made, to set the first and second tests to configure for one or more of wafer testing and package testing of the mixed signal semiconductor device. This is because Sugamori discloses semiconductor test system for testing analog/digital mixed signal integrated circuit. (See col. 7, lines 30-55).

As per claim 6, Fintel et al further disclose wherein the first and second tests are configured in an interpreted software language (23-34).

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As per claims 7-11, Fintel et al and Sugamori do not disclose wherein the interpreted software language is interactive test pascal. However, it would have been obvious to a person of ordinary skill in the art, at the time the invention was made, to interpreted software language as interactive test pascal. This is because Fintel et al disclose test database (106) using software program for testing. (See col. 2, line 50 to col. 3, line40).

As per claims 12-24 and 25-34, these claims are rejected under similar rationale as set forth in claims 1-11.

- 3. Applicant's arguments with respect to claims 1-34 have been considered but are moot in view of the new ground(s) of rejection.
- 4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Phung My Chung whose telephone number is 571-272-3818. The examiner can normally be reached on Monday to Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Albert Decady can be reached on 571-272-3819. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Phung My Chung

Primary Patent Examiner

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